

IEC QUALITY ASSESSMENT SYSTEM (IECQ)

covering Electronic Components,
Assemblies, Related Materials and Processes

For rules and details of the IECQ visit www.iecq.org

Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L ULTW 21.0001
CB Certificate No.: 50600378 ITL

Schedule Number: IECQ-L ULTW 21.0001-S Rev No.: 3 Revision Date: 2024/01/14 Page 1 of 2

Appendix-1 (50600378 ITL) Schedule of Scope to Certificate of Approval

Description test	Standard
I-V Probe station	WI-LM-0120
InGaAs microscope/Optical Beam Induced Resistance Change (OBIRCH)	WI-LM-0121
Scanning Acoustic Tomography (SAT).	WI-LM-0333
2D X-ray	WI-LM-0364
Secondary Electron Microscope (SEM)	WI-LM-0302
Electrostatic Discharge (ESD) /Latch-up (Heating by Thermo stream)	HBM: ANSI/ESDA/JEDEC JS-001; AEC-Q100-002; MIL-STD-883 MM: JED22-A115; AEC-Q100-003 CDM: ANSI/ESDA/JEDEC JS-002; JESD22-C101; AEC-Q100-011 Latch up: JESD78; AEC-Q100-004
High Temperature Operating Life (HTOL)	JEDEC-22A-108 AEC-Q100; AEC-Q101; AEC-Q200
Early Life Failure Rate (ELFR)	JESD74 AEC-Q100; AEC-Q104
High Temperature Storage test (HTST)	JEDEC-22A-103
Low Temperature Storage test (LTST)	IEC 60068-series MIL-STD-810/883 AEC-Q100; AEC-Q101; AEC-Q200
Temperature and Humidity test (THT)	IEC 60068-series MIL-STD-810/883 AEC-Q100; AEC-Q101; AEC-Q200
Highly Accelerated Stress test (HAST)	JEDEC-22A-118 MIL-STD-810/883 AEC-Q100; AEC-Q101; AEC-Q200

This schedule is only valid in conjunction with the referenced Certificate of Approval
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DQS-Group - DQS Taiwan Inc., Feng Yuan Dist., Taichung City, Taiwan



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Description test	Standard
Accelerated Moisture Resistance-Unbiases	JEDEC-22A- 110
(Unbiased HAST)	MIL-STD-810/883
	AEC-Q100; AEC-Q101; AEC-Q200
Pressure Cooker test (PCT)	JEDEC-22A-102
Temperature and Humidity with Bias test (THB)	JEDEC-22A-101
	MIL-STD-810/883
	AEC-Q100; AEC-Q101; AEC-Q200
Precondition test / Moisture Sensitivity Level	JEDEC-J-STD-020
Reflow	JEDEC-J-STD-020
	JEDEC22-B102
Solderability (SD)	IPC-J-STD-002D
Solder ball shear	JESD22-B117

Technical Reviewer of DQS:______ Date: 01/14/2024

